

Search Notes**Application/Control No.**

10/695,874

Applicant(s)/Patent under Reexamination

HAYAMI ET AL.

Examiner

Art Unit

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1765

SEARCHED

Class	Subclass	Date	Examiner
438	706	7/18/05	K-cc
	710		
	712		
	714		
	719		
	723		
	725		
438	745		
510	175		
510	176		
134	1.1		
	1.2		
134	1.3	7/18/05	K-cc

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East Key words search USPTO, US pat-pub. EPO, JPO, Derwent IBM - TDB.	7/18/05	K-cc
inventor search	7/18/05	K-cc